

**Notice of References Cited**

Application/Control No.

10/530,436

Applicant(s)/Patent Under  
Reexamination  
SHEN ET AL.

Examiner

HEE SOO KIM

Art Unit

2457

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0143972 A1	10-2002	Christopoulos et al.	709/231
*	B	US-2003/0156108 A1	08-2003	Vetro, Anthony	345/418
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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